Hybrid 6p234 Traveler

May 15, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens: PARST with wirebonds.

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 6P234 has die: 181-027 181-032 181-033 181-035 181-036 181-041

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 6p234 classification info. Created 08:44:59 05/12/00

Hybrid 6p234 quality: fair
Chip classification: good good good fair fair fair
Bad channels: none
Bad cells: none
Random bad capacitors (chip-cell-channel): 3-24-93 3-24-94 3-24-95
   3-25-94 3-8-94 4-0-115 4-11-114 4-11-115 4-2-115 4-24-115 4-41-115
   4-44-115 5-37-47
Channels at pedestal needed for DCMS: 30.6 31.7 29.6 31.6 32.6 32.6
```

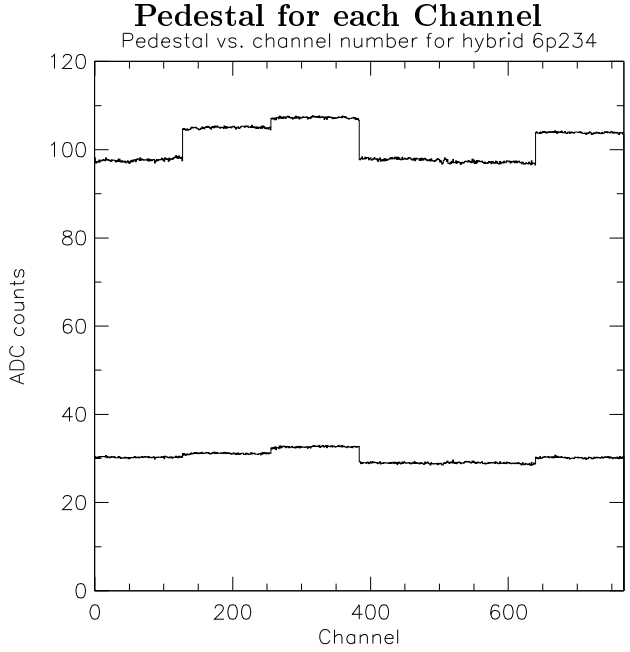
4 Comments

Encapsulated. FE DV finger gold bonds. HV tested.

5 Pedestal

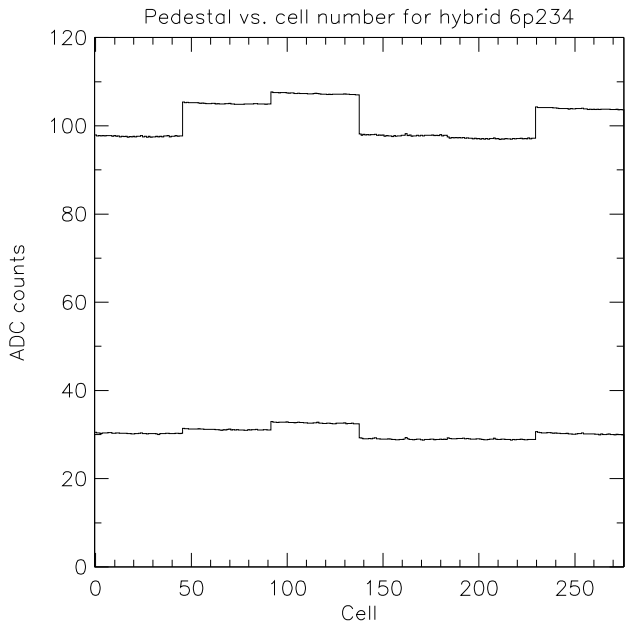
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

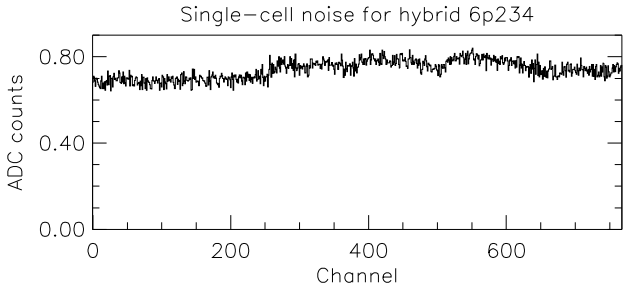
Pedestal vs. Pipeline Cell ID

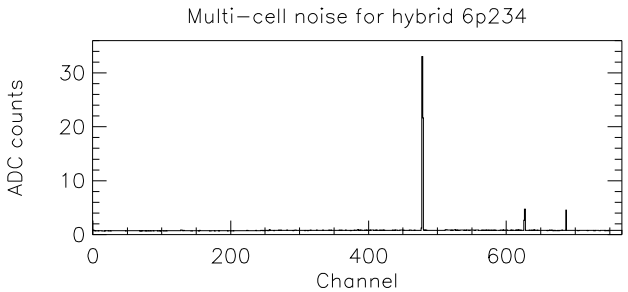


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

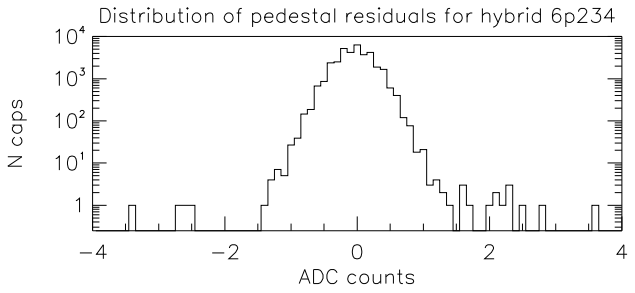
RMS Noise

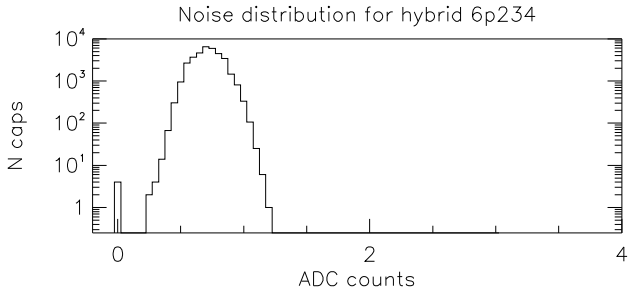




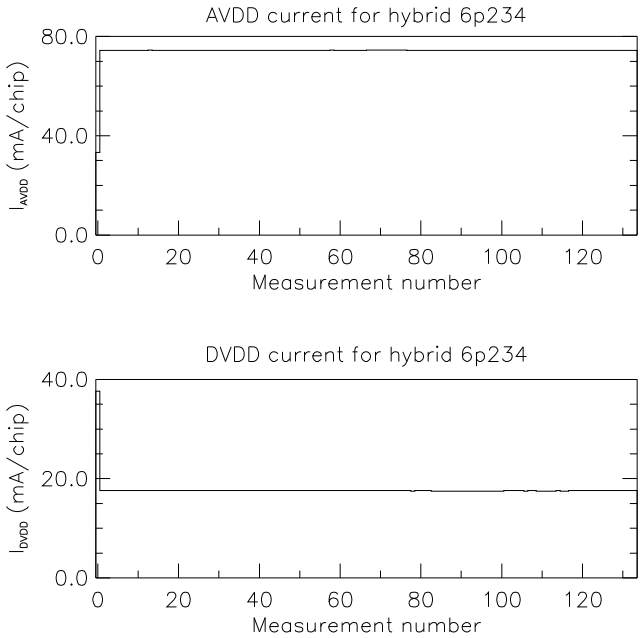
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in